

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Appln. of: James L. Hanna  
Appln. No.: Unknown  
Filed: Concurrently Herewith  
For: Crack Detection System  
Attorney Docket No: 10588-032

Examiner: Unknown  
Art Unit: Unknown

### INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56, and more particularly in accordance with 37 C.F.R. §1.97(b), Applicant cites the following references (each listed for the Examiner's convenience on the enclosed Form PTO-1449):

No.	Date of Publication	Patentee/Applicant/Assignee
3,694,658	09/26/1972	Watson et al.
4,245,913	01/20/1981	Sarlos
4,457,622	07/03/1984	Kato et al.
4,513,316	04/23/1985	Kobayashi et al.
4,544,268	10/01/1985	Yamada et al.
4,644,394	02/17/1987	Reeves
4,677,852	07/07/1987	Pinyan et al.
4,690,284	09/01/1987	Buckley et al.
4,843,884	07/04/1989	House et al.
4,894,201	01/16/1990	Ahmed
4,905,842	03/06/1990	Habele et al.
5,164,995	11/17/1992	Brooks et al.
5,383,021	01/17/1995	Hanna
5,568,263	10/22/1996	Hanna
5,646,724	07/08/1997	Hershline
5,823,356	10/20/1998	Goodrich et al.
5,835,220	11/10/1998	Kazama et al.
6,064,759	05/16/2000	Buckley et al.
6,208,417	03/27/2001	Itagaki et al.
6,266,138	07/24/2001	Keshavmurthy
6,285,034	09/04/2001	Hanna et al.
6,313,948	11/06/2001	Hanna
6,373,565	04/16/2002	Kafka et al.
6,462,813	10/08/2002	Haven et al.

6,556,298	04/29/2003	Pailliotet
2001/0028452	10/11/2001	Yoneda
2002/0015148	02/07/2002	Tomamatsu
2002/0043635	04/18/2002	Yasuda et al.
2003/0095250	05/22/2003	Kitagawa et al.
WO01/09665	02/08/2001	Hanna
OTHER PUBLICATIONS		
Emerging NDE Technologies and Challenges at the Beginning of the 3rd Millennium -- Part I, Part II, Yoseph Bar-Cohen, January 2000, Vol. 5, No. 1, pages 1-14		
Highly Accurate Linear Slides Help Laser Vision System Measure Wide Range of Parts to $\pm 0.0004$ " Tolerances, Del-Tron Precision, Inc., no date available, pages 1-4		

A copy of each listed reference for which a copy is required under 37 C.F.R. §1.98(a)(2) is also enclosed. As each of the listed references is in English, no further commentary is believed to be necessary, 37 C.F.R. §1.98(a)(3). Applicant respectfully solicits the Examiner's consideration of the listed references and entry thereof into the record of this application.

By submitting this Statement, Applicant is attempting to fully comply with the duty of candor and good faith mandated by 37 C.F.R. §1.56. As such, this Statement is not intended to constitute an admission that any of the enclosed references, or other information referred to therein, constitutes "prior art" or is otherwise "material to patentability," as that phrase is defined in 37 C.F.R. §1.56(a).

Applicant has calculated no fee to be due in connection with the filing of this Statement. However, the Commissioner is authorized to charge any fee deficiency associated with the filing of this Statement to a deposit account, as authorized in the Transmittal accompanying this Statement.

Respectfully submitted,

2/9/04  
Date

Robert K. Fergan  
Robert K. Fergan (Reg. No. 51,674)  
Attorney/Agent for Applicant

Enclosures: Form PTO-1449 (two sheets)  
Copies of listed references

FORM PTO-1449	APPLICATION NO. Unknown	CASE NO. 10588-032
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE Concurrently Herewith	ART UNIT Unknown
APPLICANT(S): James L. Hanna		

**REFERENCE DESIGNATION**
**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	3,694,658	09/26/1972	Watson, et al.		
	4,245,913	01/20/1981	Sarlos		
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**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES	NO
	WO01/09665	02/08/2001	Published Appln.			

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)
	Emerging NDE Technologies and Challenges at the Beginning of the 3rd Millennium --Part I, Part II, Yoseph Bar-Cohen, January 2000, Vol. 5, No. 1., pages 1-14
	Highly Accurate Linear Slides Help Laser Vision System Measure Wide Range of Parts to $\pm 0.0004$ " Tolerances, Del-Tron Precision, Inc., no date available, pages 1-4

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